



Shenzhen Tuofeng Semiconductor Technology Co., Ltd

**N - CHANNEL ENHANCEMENT MODE POWER MOSFET**

SGT MOS、低内阻、低结电容开关损耗小

**TF023N04NG****• General Description**

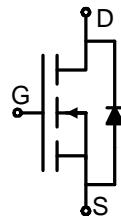
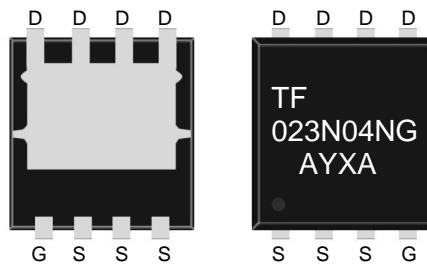
The TF023N04NG uses advanced trench technology and design to provide excellent RDS(ON) withlowgate charge. It can be used in a wide variety of applications.

**• Features**

- Advance device constructure
- Low  $R_{DS(ON)}$  to minimize conduction loss
- Low Gate Charge for fast switching
- Low Thermal resistance

**• Application**

- Synchronous Rectification for AC-DC/DC-DC converter
- Power Tools

**• Product Summary** $V_{DS} = 40V \quad I_D = 110A$  $R_{DS(ON)(10V\ typ)} = 2.3m\Omega$  $R_{DS(ON)(4.5V\ typ)} = 3.0m\Omega$ **PDFNWB5x6-8L****• Package Marking and Ordering Information:**

Part NO.	TF023N04NG
Marking1	023N04NG
Marking2	TF:tuofeng; AA:device code; Y:year code; X:Week
MOQ	5000

**• Absolute Maximum Ratings ( $T_C = 25^\circ C$ )**

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	40	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D @ T_C = 25^\circ C$	110	A
	$I_D @ T_C = 75^\circ C$	85	A
	$I_D @ T_C = 100^\circ C$	65	A
Pulsed Drain Current ①	$I_{DM}$	230	A
Total Power Dissipation	$P_D @ T_C = 25^\circ C$	65	W
Total Power Dissipation	$P_D @ T_A = 25^\circ C$	3.0	W
Operating Junction Temperature	$T_J$	-55 to 150	$^\circ C$
Storage Temperature	$T_{STG}$	-55 to 150	$^\circ C$
Single Pulse Avalanche Energy	$E_{AS}$	105	mJ



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**TF023N04NG****•Thermal resistance**

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	R <sub>thJC</sub>	-	-	1.65	° C/W
Thermal resistance, junction - ambient	R <sub>thJA</sub>	-	-	40	° C/W
Soldering temperature, wavesoldering for 8 s	T <sub>sold</sub>	-	-	265	° C

**•Electronic Characteristics**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250uA	40	-	-	V
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250uA	1.1	1.5	2.1	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> = 40 V <sub>GS</sub> = 0V	-	-	1.0	uA
Gate- Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> = ±20V , V <sub>DS</sub> = 0V	-	-	±100	nA
Static Drain-source On Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A	-	2.3	2.8	mΩ
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 20A	-	3.0	3.8	mΩ
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> = 25V, I <sub>D</sub> = 20A	-	42	-	S
Source-drain voltage	V <sub>SD</sub>	I <sub>S</sub> = 20A	-	-	1.2	V

**•Electronic Characteristics**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Input capacitance	C <sub>iss</sub>	f = 1MHz V <sub>DS</sub> = 20V V <sub>GS</sub> = 0V	-	2800	-	pF
Output capacitance	C <sub>oss</sub>		-	1070	-	
Reverse transfer capacitance	C <sub>rss</sub>		-	110	-	

**•Gate Charge characteristics(T<sub>a</sub> = 25°C)**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Gate Resistance	R <sub>g</sub>	f = 1MHz		1.7		Ω
Total gate charge	Q <sub>g</sub>	V <sub>DD</sub> = 20V I <sub>D</sub> = 20A V <sub>GS</sub> = 10V	-	46.0	-	nC
Gate - Source charge	Q <sub>gs</sub>		-	8.7	-	
Gate - Drain charge	Q <sub>gd</sub>		-	5.4	-	
Turn-ON Delay time	t <sub>D(on)</sub>	V <sub>GS</sub> = 10V , V <sub>DS</sub> = 20V R <sub>G</sub> = 3.0Ω, I <sub>D</sub> = 20A		4.00		ns
Turn-ON Rise time	t <sub>r</sub>			5.00		ns
Turn-Off Delay time	t <sub>D(off)</sub>			35.0		ns
Turn-Off Fall time	t <sub>f</sub>			11.0		ns
Reverse Recovery Time	trr	V <sub>GS</sub> = 0V, I <sub>S</sub> = 20A dI <sub>S</sub> /dt = 100A/μs		43.0		ns
Reverse Recovery Charge	Qrr			53.0		nC

Note: ① Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2% ;



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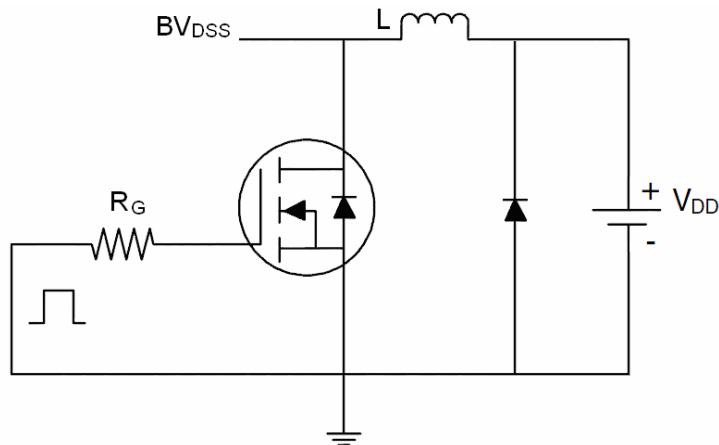
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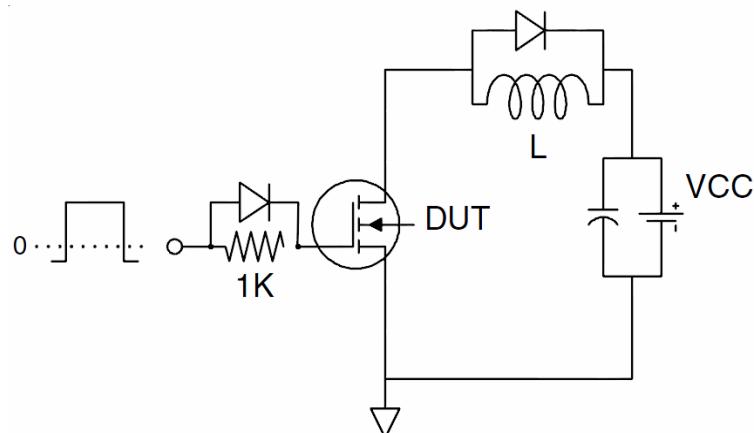
**TF023N04NG**

### Test Circuit

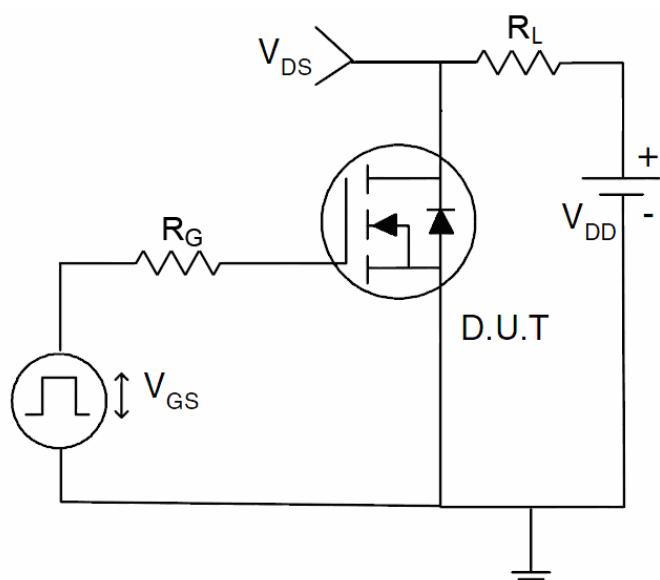
#### 1) E<sub>AS</sub> test Circuit



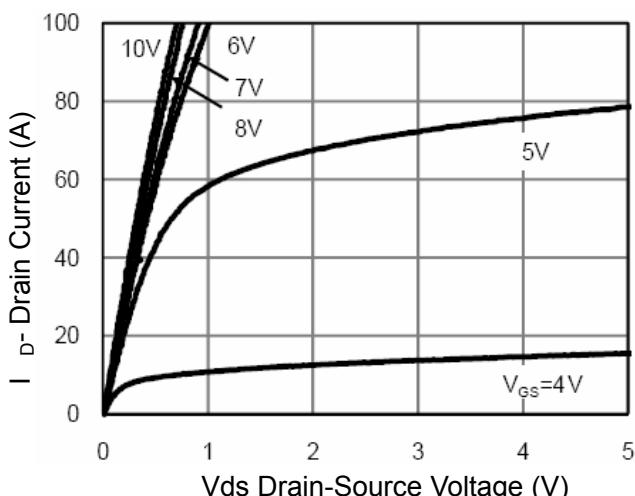
#### 2) Gate charge test Circuit



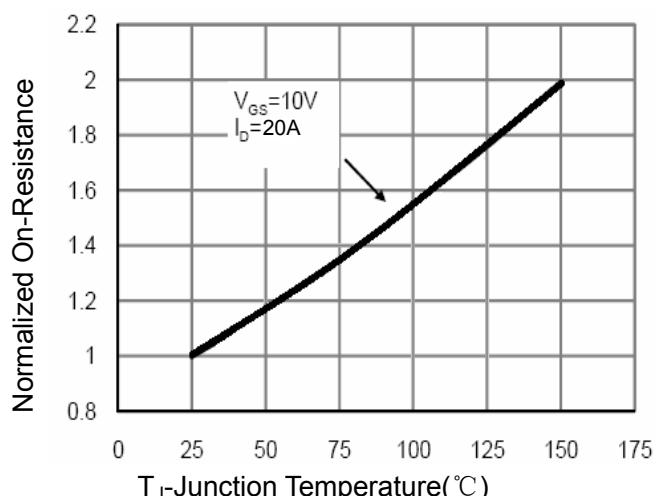
#### 3) Switch Time Test Circuit



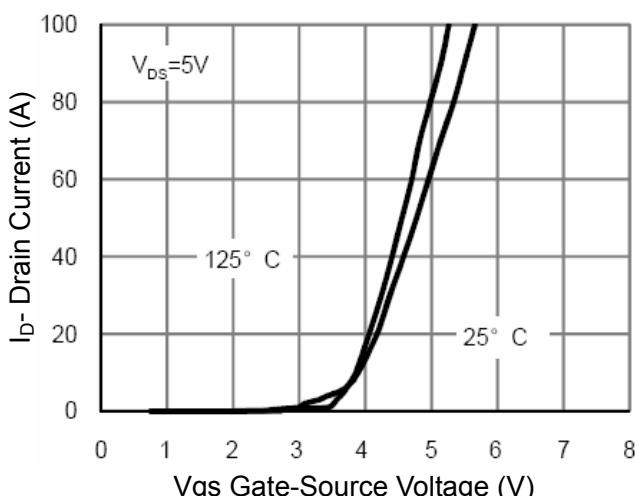
### Typical Electrical and Thermal Characteristics



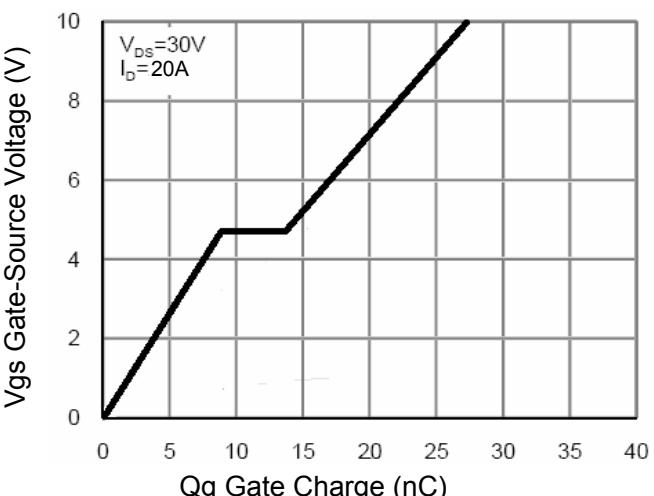
**Figure 1 Output Characteristics**



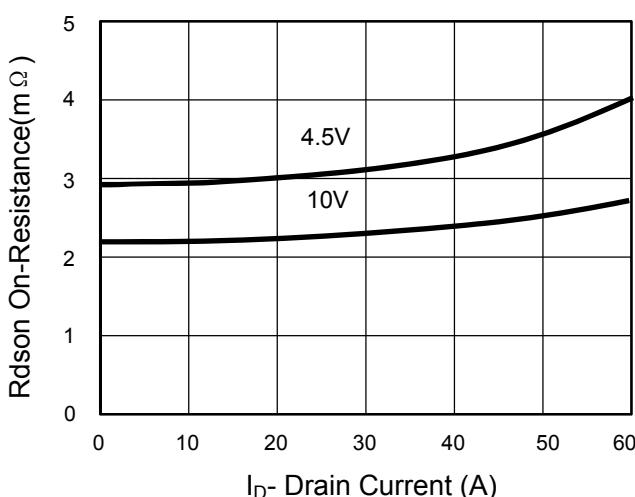
**Figure 4 Rdson-JunctionTemperature**



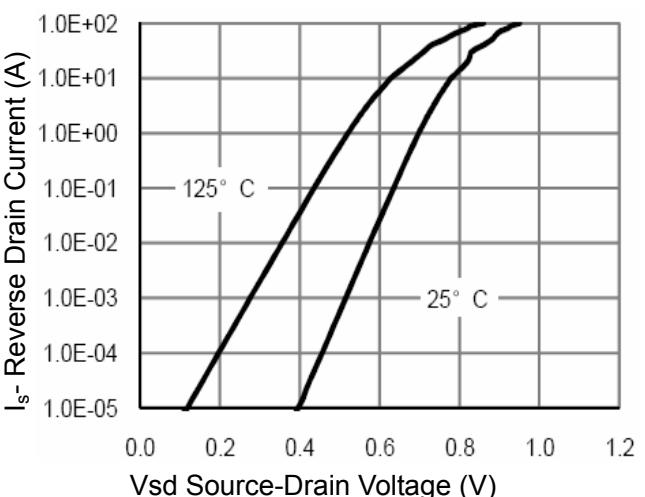
**Figure 2 Transfer Characteristics**



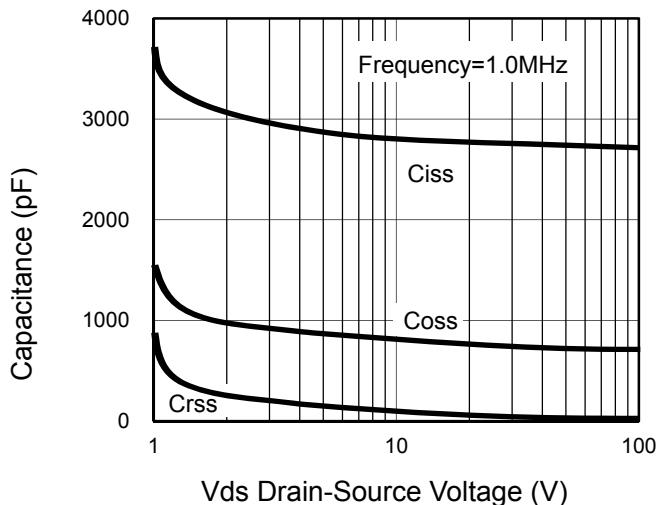
**Figure 5 Gate Charge**



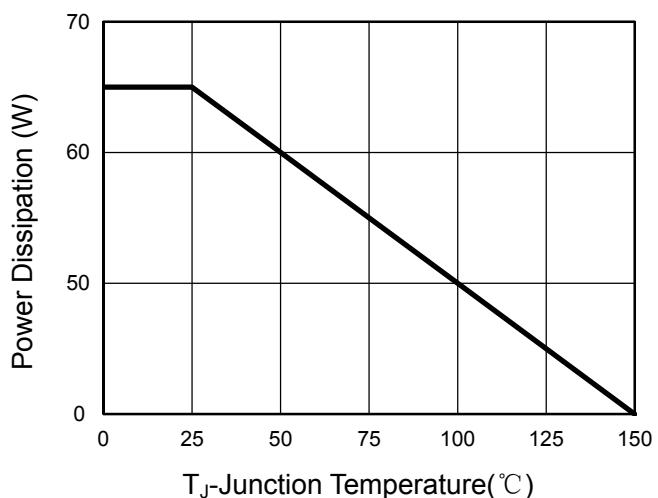
**Figure 3 Rdson- Drain Current**



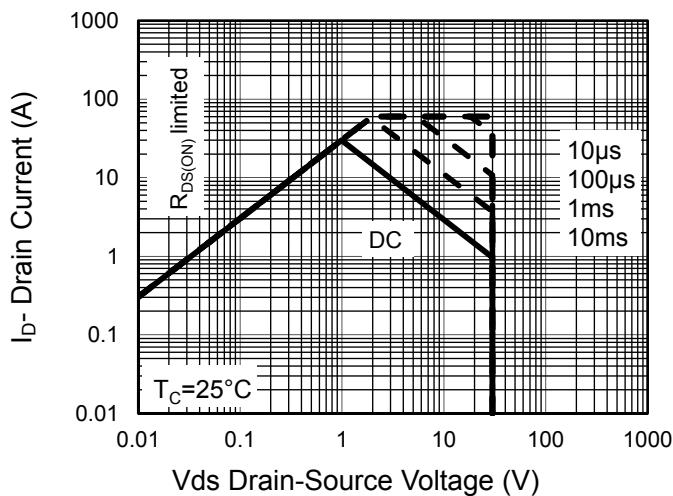
**Figure 6 Source- Drain Diode Forward**



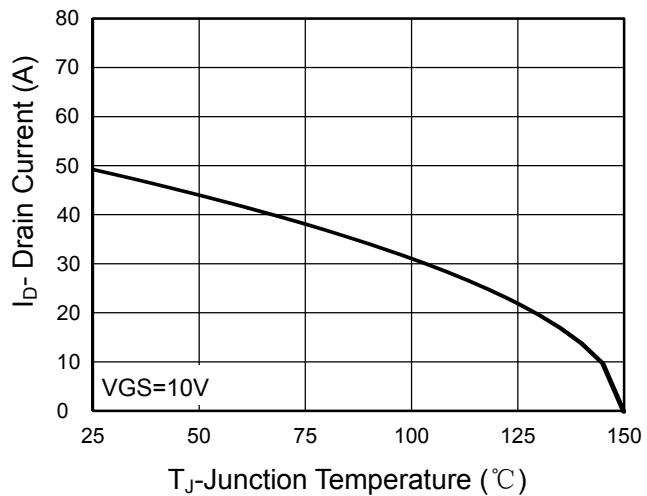
**Figure 7 Capacitance vs Vds**



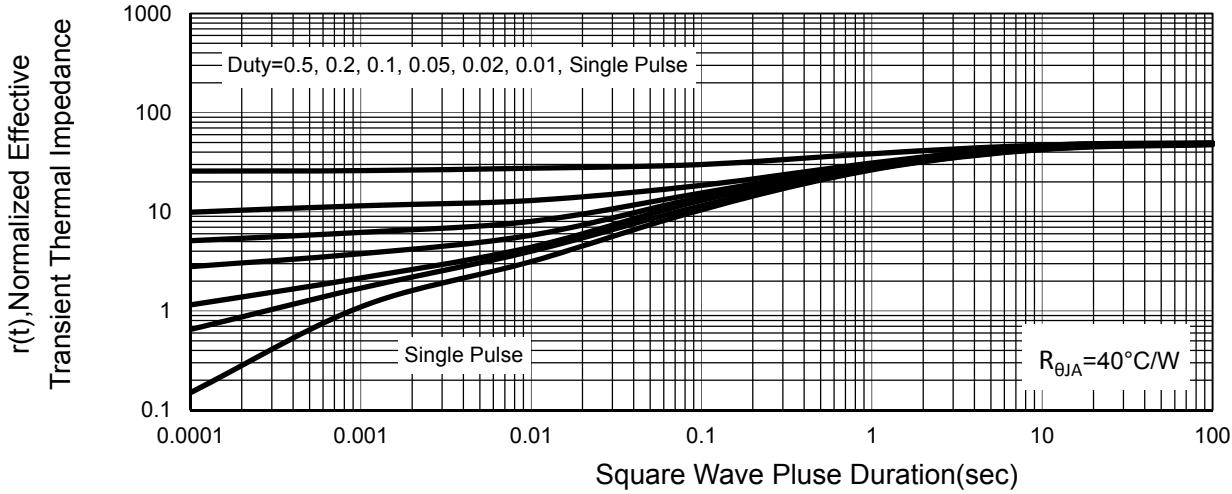
**Figure 9 Power De-rating**



**Figure 8 Safe Operation Area**



**Figure 10 Current De-rating**



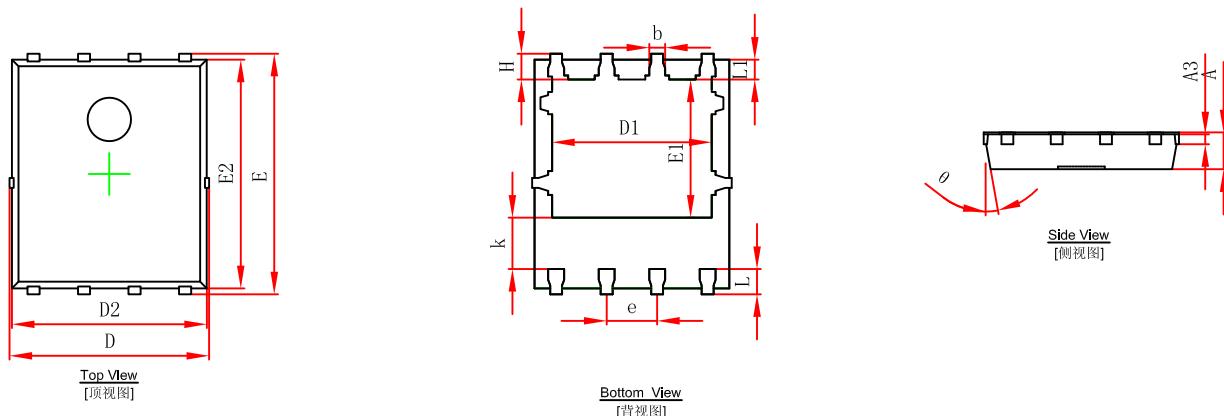
**Figure 11 Normalized Maximum Transient Thermal Impedance**



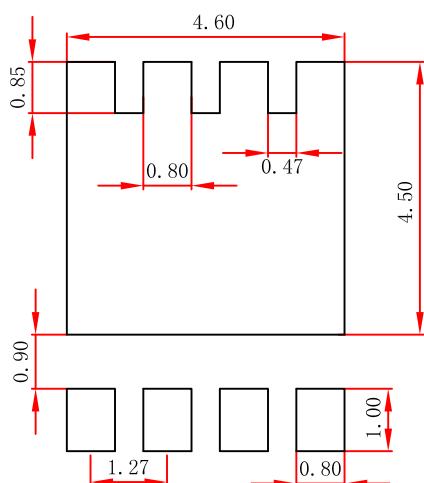
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**TF023N04NG****PDFNWB5x6-8L Package Outline Dimensions**

Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039
A3	0.254REF.		0.010REF.	
D	4.944	5.096	0.195	0.201
E	5.974	6.126	0.235	0.241
D1	3.910	4.110	0.154	0.162
E1	3.375	3.575	0.133	0.141
D2	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.390	0.047	0.055
b	0.350	0.450	0.014	0.018
e	1.270TYP.		0.050TYP.	
L	0.559	0.711	0.022	0.028
L1	0.424	0.576	0.017	0.023
H	0.574	0.726	0.023	0.029
θ	10°	12°	10°	12°

**PDFNWB5x6-8L Suggested Pad Layout**

Note:  
1. Controlling dimension:in millimeters.  
2. General tolerance: $\pm 0.05\text{mm}$ .  
3. The pad layout is for reference purposes only.